FEATURES
5 MHz to 20 MHz external clock input rate
16 bits, no missing codes
Signal-to-noise ratio (SNR): 88 dB typical
Effective number of bits (ENOB): 14.2 bits typical
Typical offset drift vs. temperature: 1.6 µV/°C typical
On-board digital isolator
On-board reference
Full-scale analog input range: ±320 mV
−40°C to + 125°C operating range
High common-mode transient immunity: >25 kV/µs
16-lead, wide-body SOIC, with increased creepage package
Slew rate limited output for low electromagnetic interference (EMI)

Safety and regulatory approvals
UL recognition
5000 V rms for 1 minute per UL 1577
CSA Component Acceptance Notice 5A
VDE Certificate of Conformity
DIN V VDE V 0884-10 (VDE V 0884-10):2006-12
$V_{FORM} = 1250 V_{PEAK}$

APPLICATIONS
Shunt current monitoring
AC motor controls
Power and solar inverters
Wind turbine inverters
Data acquisition systems
Analog-to-digital and opto-isolator replacements

GENERAL DESCRIPTION
The AD7403 is a high performance, second-order, Σ-Δ modulator that converts an analog input signal into a high speed, single-bit data stream, with on-chip digital isolation based on Analog Devices, Inc., iCoupler® technology. The AD7403 operates from a 5 V ($V_{DD1}$) power supply and accepts a differential input signal of ±250 mV (±320 mV full-scale). The differential input is ideally suited to shunt voltage monitoring in high voltage applications where galvanic isolation is required.

The analog input is continuously sampled by a high performance analog modulator, and converted to a ones density digital output stream with a data rate of up to 20 MHz. The original information can be reconstructed with an appropriate digital filter to achieve 88 dB signal to noise ratio (SNR) at 78.1 kSPS. The serial input/output can use a 5 V or a 3 V supply ($V_{DD2}$).

The serial interface is digitally isolated. High speed complementary metal oxide semiconductor (CMOS) technology, combined with monolithic transformer technology, means the on-chip isolation provides outstanding performance characteristics, superior to alternatives such as optocoupler devices. The AD7403 device is offered in a 16-lead, wide-body SOIC package and has an operating temperature range of −40°C to +125°C.
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REVISION HISTORY

11/14—Rev. 0 to Rev. A  
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4/14—Revision 0: Initial Version
**SPECIFICATIONS**

\( V_{\text{DD1}} = 4.5 \text{ V to } 5.5 \text{ V}, V_{\text{DD2}} = 3 \text{ V to } 5.5 \text{ V}, V_{\text{IN+}} = -250 \text{ mV to +250 mV}, V_{\text{IN-}} = 0 \text{ V}, T_A = -40^\circ\text{C to +125^\circC}, f_{\text{MCLKIN}}^1 = 5 \text{ MHz to } 20 \text{ MHz}, \) tested with sinc3 filter, 256 decimation rate, as defined by Verilog code, unless otherwise noted. All voltages are relative to their respective ground.

| Table 1. |
|---------------------------------|-------|-------|----------------|
| **Parameter**                    | **Min** | **Typ** | **Max**       |
| **STATIC PERFORMANCE**           |        |        |               |
| Resolution                       | 16     | ±12   | Bits          |
| Integral Nonlinearity (INL)\(^2\) | ±2     | ±12   | LSB           |
| Differential Nonlinearity (DNL)\(^2\) | ±0.99  | ±0.75 | mV            |
| Offset Error\(^2\)               | ±0.2   | ±0.75 | mV            |
| Offset Drift vs. Temperature     | 1.3    | 3.1   | μV/°C         |
| Offset Drift vs. \(V_{\text{DD1}}\) | 50   | ±0.8  | μV/V          |
| Gain Error\(^2\)                 | ±0.2   | ±0.8  | % FSR         |
| Gain Error Drift vs. Temperature | 65     | 95    | ppm/°C        |
| Gain Error Drift vs. \(V_{\text{DD1}}\) | ±0.6  | ±0.6  | mV/V          |
| **ANALOG INPUT**                 |        |        |               |
| Input Voltage Range              | −320   | +320  | mV            |
| Dynamic Input Current            | ±45    | ±50   | μA            |
| DC Leakage Current               | ±0.01  | ±0.6  | μA            |
| **DYNAMIC SPECIFICATIONS**       |        |        |               |
| Signal-to-Noise-and-Distortion Ratio (SINAD)\(^2\) | 81  | 87    | dB            |
| Signal-to-Noise Ratio (SNR)\(^2\) | 83    | 87    | dB            |
| Total Harmonic Distortion (THD)\(^2\) | 86    | 88    | dB            |
| Peak Harmonic or Spurious Noise (SFDR)\(^2\) | 96    | -97   | dB            |
| Effective Number of Bits (ENOB)\(^2\) | 13.1 | 14.2  | Bits          |
| Noise Free Code Resolution\(^2\) | 13.4  | 14.2  | Bits          |
| **ISOLATION TRANSIENT IMMUNITY** | 25     | 30    | kV/μs         |
| **LOGIC INPUTS**                 |        |        |               |
| Input High Voltage (\(V_{\text{IH}}\)) | 0.8 \times \(V_{\text{DD2}}\) | \(V\) |
| Input Low Voltage (\(V_{\text{IL}}\)) | 0.2 \times \(V_{\text{DD2}}\) | \(V\) |
| Input Current (\(I_{\text{I}}\)) | ±0.6   | μA    |
| Input Capacitance (\(C_{\text{I}}\)) | 10    | pF    |
| **LOGIC OUTPUTS**                |        |        |               |
| Output High Voltage (\(V_{\text{OH}}\)) | \(V_{\text{DD2}} - 0.1\) | \(V\) |
| Output Low Voltage (\(V_{\text{OL}}\)) | 0.4   | \(V\) | \(I_O = -200 \mu A\) |

\(^1\) \text{ Tested with } sinc3 \text{ filter, } 256 \text{ decimation rate, as defined by Verilog code, unless otherwise noted.} 

\(^2\) \text{ All voltages are relative to their respective ground.}
**POWER REQUIREMENTS**

<table>
<thead>
<tr>
<th>Parameter</th>
<th>Min</th>
<th>Typ</th>
<th>Max</th>
<th>Unit</th>
<th>Test Conditions/Comments</th>
</tr>
</thead>
<tbody>
<tr>
<td>VDD1</td>
<td>4.5</td>
<td>5.5</td>
<td>V</td>
<td></td>
<td></td>
</tr>
<tr>
<td>VDD2</td>
<td>3</td>
<td>5.5</td>
<td>V</td>
<td></td>
<td></td>
</tr>
<tr>
<td>IDD1</td>
<td>30</td>
<td>36</td>
<td>mA</td>
<td>VDD1 = 5.5 V</td>
<td></td>
</tr>
<tr>
<td>IDD2</td>
<td>12</td>
<td>18</td>
<td>mA</td>
<td>VDD2 = 5.5 V</td>
<td></td>
</tr>
<tr>
<td></td>
<td>6</td>
<td>10</td>
<td>mA</td>
<td>VDD2 = 3.3 V</td>
<td></td>
</tr>
<tr>
<td>Power Dissipation</td>
<td>231</td>
<td>297</td>
<td>mW</td>
<td>VDD1 = VDD2 = 5.5 V</td>
<td></td>
</tr>
<tr>
<td></td>
<td>185</td>
<td>231</td>
<td>mW</td>
<td>VDD1 = 5.5 V, VDD2 = 3.3 V</td>
<td></td>
</tr>
</tbody>
</table>

1 For fMCLKIN > 16 MHz, mark space ratio is 48/52 to 52/48, VDD1 = 5 V ± 5%.
2 See the Terminology section.

**TIMING SPECIFICATIONS**

VDD1 = 4.5 V to 5.5 V, VDD2 = 3 V to 5.5 V, T_A = −40°C to +125°C, unless otherwise noted. Sample tested during initial release to ensure compliance. It is recommended to read MDAT on the MCLKIN rising edge.

<table>
<thead>
<tr>
<th>Parameter</th>
<th>Limit at T_MIN, T_MAX</th>
<th>Unit</th>
<th>Description</th>
</tr>
</thead>
<tbody>
<tr>
<td>fMCLKIN</td>
<td>5 MHz minimum</td>
<td>MHz</td>
<td>Master clock input frequency</td>
</tr>
<tr>
<td></td>
<td>20 MHz maximum</td>
<td>MHz</td>
<td></td>
</tr>
<tr>
<td>t1</td>
<td>40 ns maximum</td>
<td>ns</td>
<td>Data access time after MCLKIN rising edge</td>
</tr>
<tr>
<td></td>
<td>45 ns maximum</td>
<td>ns</td>
<td>VDD2 = 4.5 V to 5.5 V</td>
</tr>
<tr>
<td></td>
<td>12 ns minimum</td>
<td>ns</td>
<td>VDD2 = 3 V to 3.6 V</td>
</tr>
<tr>
<td></td>
<td>17 ns minimum</td>
<td>ns</td>
<td>VDD2 = 4.5 V to 5.5 V</td>
</tr>
<tr>
<td></td>
<td>0.45 × tMCLKIN</td>
<td>ns</td>
<td>Master clock low time</td>
</tr>
<tr>
<td></td>
<td>0.48 × tMCLKIN</td>
<td>ns</td>
<td>fMCLKIN ≤ 16 MHz</td>
</tr>
<tr>
<td></td>
<td>16 MHz &lt; fMCLKIN ≤ 20 MHz</td>
<td></td>
<td></td>
</tr>
<tr>
<td>t4</td>
<td>0.45 × tMCLKIN</td>
<td>ns</td>
<td>Master clock high time</td>
</tr>
<tr>
<td></td>
<td>0.48 × tMCLKIN</td>
<td>ns</td>
<td>fMCLKIN ≤ 16 MHz</td>
</tr>
<tr>
<td></td>
<td>16 MHz &lt; fMCLKIN ≤ 20 MHz</td>
<td></td>
<td></td>
</tr>
</tbody>
</table>

1 Defined as the time required from an 80% MCLKIN input level to when the output crosses 0.8 V or 2.0 V for VDD2 = 3 V to 3.6 V or when the output crosses 0.8 V or 0.7 × VDD2 for VDD2 = 4.5 V to 5.5 V as outlined in Figure 2. Measured with a ±200 µA load and a 25 pF load capacitance.

![Figure 2. Data Timing](image)

1 SEE NOTE 1 OF TABLE 2 FOR FURTHER DETAILS
### PACKAGE CHARACTERISTICS

Table 3.

<table>
<thead>
<tr>
<th>Parameter</th>
<th>Symbol</th>
<th>Min</th>
<th>Typ</th>
<th>Max</th>
<th>Unit</th>
<th>Test Conditions/Comments</th>
</tr>
</thead>
<tbody>
<tr>
<td>Resistance (Input to Output)¹</td>
<td>RI-O</td>
<td>10</td>
<td>12</td>
<td>10</td>
<td>Ω</td>
<td>f = 1 MHz</td>
</tr>
<tr>
<td>Capacitance (Input to Output)¹</td>
<td>CI-O</td>
<td>2.2</td>
<td></td>
<td></td>
<td>pF</td>
<td></td>
</tr>
<tr>
<td>IC Junction to Ambient Thermal Resistance</td>
<td>θJA</td>
<td>45</td>
<td></td>
<td></td>
<td>°C/W</td>
<td>Thermocouple located at center of package underside, test conducted on 4-layer board with thin traces</td>
</tr>
</tbody>
</table>

¹ The device is considered a 2-terminal device: Pin 1 to Pin 8 are shorted together, and Pin 9 to Pin 16 are shorted together.

### INSULATION AND SAFETY RELATED SPECIFICATIONS

Table 4.

<table>
<thead>
<tr>
<th>Parameter</th>
<th>Symbol</th>
<th>Value</th>
<th>Unit</th>
<th>Test Conditions/Comments</th>
</tr>
</thead>
<tbody>
<tr>
<td>Input to Output Momentary Withstand Voltage</td>
<td>VISO</td>
<td>5000</td>
<td>V</td>
<td>1 minute duration</td>
</tr>
<tr>
<td>Minimum External Air Gap (Clearance)</td>
<td>L(I01)</td>
<td>8.3 min¹ ²</td>
<td>mm</td>
<td>Measured from input terminals to output terminals, shortest distance through air</td>
</tr>
<tr>
<td>Minimum External Tracking (Creepage)</td>
<td>L(I02)</td>
<td>8.3 min¹</td>
<td>mm</td>
<td>Measured from input terminals to output terminals, shortest distance path along body</td>
</tr>
<tr>
<td>Minimum Internal Gap (Internal Clearance)</td>
<td>CTI</td>
<td>0.034 mm</td>
<td>mm</td>
<td>Distance through insulation</td>
</tr>
<tr>
<td>Tracking Resistance (Comparative Tracking Index)</td>
<td>CTI</td>
<td>&gt;400</td>
<td>V</td>
<td>DIN IEC 112/VDE 0303 Part 1³</td>
</tr>
<tr>
<td>Isolation Group</td>
<td></td>
<td></td>
<td>II</td>
<td>Material Group (DIN VDE 0110, 1/89, Table I)</td>
</tr>
</tbody>
</table>

¹ In accordance with IEC 60950-1 guidelines for the measurement of creepage and clearance distances for a pollution degree of 2 and altitudes ≤2000 m.
² Consideration must be given to pad layout to ensure the minimum required distance for clearance is maintained.
³ CSA CTI rating for the AD7403 is >600 V and a Material Group I isolation group.

### REGULATORY INFORMATION

The AD7403 is approved by the organizations listed in Table 5.

Table 5.

<table>
<thead>
<tr>
<th>UL¹</th>
<th>CSA</th>
<th>VDE²</th>
</tr>
</thead>
<tbody>
<tr>
<td>Recognized under 1577 Component Recognition Program¹</td>
<td>Approved under CSA Component Acceptance Notice 5A</td>
<td>Certified according to DIN V VDE V 0884-10 (VDE V 0884-10):2006-12²</td>
</tr>
<tr>
<td>5000 V rms Isolation Voltage Single Protection</td>
<td>Basic insulation per CSA 60950-1-07 and IEC 60950-1, 830 V rms (1173 VPEAK) maximum working voltage³</td>
<td>Reinforced insulation per DIN V VDE V 0884-10 (VDE V 0884-10):2006-12, 1250 VPEAK</td>
</tr>
<tr>
<td></td>
<td>Reinforced insulation per CSA 60950-1-07 and IEC 60950-1, 415 V rms (586 VPEAK) maximum working voltage³</td>
<td></td>
</tr>
<tr>
<td></td>
<td>Reinforced insulation per IEC 60601-1, 250 V rms (353 VPEAK) maximum working voltage³</td>
<td></td>
</tr>
<tr>
<td></td>
<td>File E214100</td>
<td>File 2471900-4880-0001</td>
</tr>
</tbody>
</table>

¹ In accordance with UL 1577, each AD7403 is proof tested by applying an insulation test voltage ≥ 6000 V rms for 1 second (current leakage detection limit = 15 µA).
² In accordance with DIN V VDE V 0884-10, each AD7403 is proof tested by applying an insulation test voltage ≥ 2344 VPEAK for 1 second (partial discharge detection limit = 5 pC).
³ Rating is calculated for a pollution degree of 2 and a Material Group III. The AD7403 RI-16-2 package material is rated by CSA to a CTI of >600 V and therefore Material Group I.
DIN V VDE V 0884-10 (VDE V 0884-10):2006-12 INSULATION CHARACTERISTICS

This isolator is suitable for reinforced electrical isolation only within the safety limit data. Maintenance of the safety data is ensured by means of protective circuits.

Table 6.

<table>
<thead>
<tr>
<th>Description</th>
<th>Symbol</th>
<th>Characteristic</th>
<th>Unit</th>
</tr>
</thead>
<tbody>
<tr>
<td>INSTALLATION CLASSIFICATION PER DIN VDE 0110</td>
<td></td>
<td></td>
<td></td>
</tr>
<tr>
<td>For Rated Mains Voltage ≤300 V rms</td>
<td></td>
<td>I to IV</td>
<td></td>
</tr>
<tr>
<td>For Rated Mains Voltage ≤450 V rms</td>
<td></td>
<td>I to IV</td>
<td></td>
</tr>
<tr>
<td>For Rated Mains Voltage ≤600 V rms</td>
<td></td>
<td>I to IV</td>
<td></td>
</tr>
<tr>
<td>For Rated Mains Voltage ≤1000 V rms</td>
<td></td>
<td>I to IV</td>
<td></td>
</tr>
<tr>
<td>CLIMATIC CLASSIFICATION</td>
<td></td>
<td>40/105/21</td>
<td></td>
</tr>
<tr>
<td>POLLUTION DEGREE (DIN VDE 0110, TABLE 1)</td>
<td></td>
<td>2</td>
<td></td>
</tr>
<tr>
<td>MAXIMUM WORKING INSULATION VOLTAGE</td>
<td>VORM</td>
<td>1250</td>
<td>V PEAK</td>
</tr>
<tr>
<td>INPUT TO OUTPUT TEST VOLTAGE, METHOD B1</td>
<td>VORM</td>
<td>× 1.875 = VPB, 100% Production Test, tm = 1 Second, Partial Discharge &lt; 5 pC</td>
<td>VPB</td>
</tr>
<tr>
<td>INPUT TO OUTPUT TEST VOLTAGE, METHOD A</td>
<td>VORM</td>
<td>× 1.6 = VPB, tm = 60 Seconds, Partial Discharge &lt; 5 pC</td>
<td>VPB</td>
</tr>
<tr>
<td>After Environmental Test Subgroup 1</td>
<td>VORM</td>
<td>× 1.2 = VPB, tm = 60 Seconds, Partial Discharge &lt; 5 pC</td>
<td>VPB</td>
</tr>
<tr>
<td>After Input and/or Safety Test Subgroup 2/ Safety Test Subgroup 3</td>
<td>VORM</td>
<td>× 1.2 = VPB, tm = 60 Seconds, Partial Discharge &lt; 5 pC</td>
<td>VPB</td>
</tr>
<tr>
<td>HIGHEST ALLOWABLE OVERVOLTAGE (TRANSIENT OVERVOLTAGE, tm = 10 Seconds)</td>
<td>VORM</td>
<td>× 1.875 = VPB, 100% Production Test, tm = 1 Second, Partial Discharge &lt; 5 pC</td>
<td>VPB</td>
</tr>
<tr>
<td>SURGE ISOLATION VOLTAGE</td>
<td>VORM</td>
<td>× 1.6 = VPB, tm = 60 Seconds, Partial Discharge &lt; 5 pC</td>
<td>VPB</td>
</tr>
<tr>
<td>SAFETY LIMITING VALUES (MAXIMUM VALUE ALLOWED IN THE EVENT OF A FAILURE, SEE Figure 3)</td>
<td>VORM</td>
<td>× 1.2 = VPB, tm = 60 Seconds, Partial Discharge &lt; 5 pC</td>
<td>VPB</td>
</tr>
<tr>
<td>Case Temperature</td>
<td>TS</td>
<td>150</td>
<td>°C</td>
</tr>
<tr>
<td>Side 1 (PVDD1) and Side 2 (PVDD2) Power Dissipation</td>
<td>PSO</td>
<td>2.78</td>
<td>W</td>
</tr>
<tr>
<td>INSULATION RESISTANCE AT TS, VIO = 500 V</td>
<td>RIO</td>
<td>&gt;10¹¹</td>
<td>Ω</td>
</tr>
</tbody>
</table>

Figure 3. Thermal Derating Curve, Dependence of Safety Limiting Values with Case Temperature per DIN V VDE V 0884-10
ABSOLUTE MAXIMUM RATINGS

$T_a = 25^\circ C$, unless otherwise noted. All voltages are relative to their respective ground.

Table 7.

<table>
<thead>
<tr>
<th>Parameter</th>
<th>Rating</th>
</tr>
</thead>
<tbody>
<tr>
<td>$V_{DD1}$ to GND$_1$</td>
<td>$-0.3 \text{ V to } +6.5 \text{ V}$</td>
</tr>
<tr>
<td>$V_{DD2}$ to GND$_2$</td>
<td>$-0.3 \text{ V to } +6.5 \text{ V}$</td>
</tr>
<tr>
<td>Analog Input Voltage to GND$_1$</td>
<td>$-1 \text{ V to } V_{DD1} + 0.3 \text{ V}$</td>
</tr>
<tr>
<td>Digital Input Voltage to GND$_2$</td>
<td>$-0.3 \text{ V to } V_{DD2} + 0.5 \text{ V}$</td>
</tr>
<tr>
<td>Output Voltage to GND$_1$</td>
<td>$-0.3 \text{ V to } V_{DD2} + 0.3 \text{ V}$</td>
</tr>
<tr>
<td>Input Current to Any Pin Except Supplies$^1$</td>
<td>$\pm 10 \text{ mA}$</td>
</tr>
<tr>
<td>Operating Temperature Range</td>
<td>$-40^\circ C$ to $+125^\circ C$</td>
</tr>
<tr>
<td>Storage Temperature Range</td>
<td>$-65^\circ C$ to $+150^\circ C$</td>
</tr>
<tr>
<td>Junction Temperature</td>
<td>$150^\circ C$</td>
</tr>
<tr>
<td>Pb-Free Temperature, Soldering Reflow</td>
<td>$260^\circ C$</td>
</tr>
<tr>
<td>ESD</td>
<td>$2 \text{ kV}$</td>
</tr>
<tr>
<td>FICDM$^2$</td>
<td>$\pm 1250 \text{ V}$</td>
</tr>
<tr>
<td>HBM$^3$</td>
<td>$\pm 4000 \text{ V}$</td>
</tr>
</tbody>
</table>

$^1$ Transient currents of up to 100 mA do not cause SCR to latch up.
$^2$ JESD22-C101; RC network: 1 $\Omega$, Cpkg; Class: IV
$^3$ ESDA/JEDEC JS-001-2011; RC network: 1.5 $\text{k}\Omega$, 100 pF; Class: 3A

Stresses at or above those listed under Absolute Maximum Ratings may cause permanent damage to the product. This is a stress rating only; functional operation of the product at these or any other conditions above those indicated in the operational section of this specification is not implied. Operation beyond the maximum operating conditions for extended periods may affect product reliability.

Table 8. Maximum Continuous Working Voltage$^1$

<table>
<thead>
<tr>
<th>Parameter</th>
<th>Max</th>
<th>Unit</th>
<th>Constraint</th>
</tr>
</thead>
<tbody>
<tr>
<td>AC Voltage</td>
<td></td>
<td></td>
<td></td>
</tr>
<tr>
<td>Bipolar Waveform</td>
<td>1250</td>
<td>V$_{PEAK}$</td>
<td>20-year minimum lifetime (VDE approved working voltage)</td>
</tr>
<tr>
<td>Unipolar Waveform</td>
<td>1250</td>
<td>V$_{PEAK}$</td>
<td>20-year minimum lifetime</td>
</tr>
<tr>
<td>DC Voltage</td>
<td>1250</td>
<td>V$_{PEAK}$</td>
<td>20-year minimum lifetime</td>
</tr>
</tbody>
</table>

$^1$ Refers to continuous voltage magnitude imposed across the isolation barrier.

ESD CAUTION

ESD (electrostatic discharge) sensitive device. Charged devices and circuit boards can discharge without detection. Although this product features patented or proprietary protection circuitry, damage may occur on devices subjected to high energy ESD. Therefore, proper ESD precautions should be taken to avoid performance degradation or loss of functionality.
### PIN CONFIGURATION AND FUNCTION DESCRIPTIONS

#### Figure 4. Pin Configuration

![AD7403 Top View](image)

<table>
<thead>
<tr>
<th>Pin No.</th>
<th>Mnemonic</th>
<th>Description</th>
</tr>
</thead>
<tbody>
<tr>
<td>1, 7</td>
<td>VDD1</td>
<td>Supply Voltage. 4.5 V to 5.5 V. This is the supply voltage for the isolated side of the AD7403 and is relative to GND1. For device operation, connect the supply voltage to both Pin 1 and Pin 7. Decouple each supply pin to GND1 with a 10 μF capacitor in parallel with a 1 nF capacitor.</td>
</tr>
<tr>
<td>2</td>
<td>VIN+</td>
<td>Positive Analog Input.</td>
</tr>
<tr>
<td>3</td>
<td>VIN−</td>
<td>Negative Analog Input. Normally connected to GND1.</td>
</tr>
<tr>
<td>4, 8</td>
<td>GND1</td>
<td>Ground 1. This pin is the ground reference point for all circuitry on the isolated side.</td>
</tr>
<tr>
<td>5, 6</td>
<td>NIC</td>
<td>Not Internally Connected. These pins are not internally connected. Connect to VDD1, GND1, or leave floating.</td>
</tr>
<tr>
<td>9, 16</td>
<td>GND2</td>
<td>Ground 2. This pin is the ground reference point for all circuitry on the nonisolated side.</td>
</tr>
<tr>
<td>10, 12, 15</td>
<td>NIC</td>
<td>Not Internally Connected. These pins are not internally connected. Connect to VDD2, GND2, or leave floating.</td>
</tr>
<tr>
<td>11</td>
<td>MDAT</td>
<td>Serial Data Output. The single bit modulator output is supplied to this pin as a serial data stream. The bits are clocked out on the rising edge of the MCLKIN input and are valid on the following MCLKIN rising edge.</td>
</tr>
<tr>
<td>13</td>
<td>MCLKIN</td>
<td>Master Clock Logic Input. 5 MHz to 20 MHz frequency range. The bit stream from the modulator is propagated on the rising edge of the MCLKIN.</td>
</tr>
<tr>
<td>14</td>
<td>VDD2</td>
<td>Supply Voltage. 3 V to 5.5 V. This is the supply voltage for the nonisolated side and is relative to GND2. Decouple this supply to GND2 with a 100 nF capacitor.</td>
</tr>
</tbody>
</table>
TYPICAL PERFORMANCE CHARACTERISTICS

$T_A = 25^\circ C$, $V_{DD1} = 5$ V, $V_{DD2} = 5$ V, $V_{IN+} = -250$ mV to +250 mV, $V_{IN-} = 0$ V, $f_{MCLKIN} = 20$ MHz, using a sinc3 filter with a 256 oversampling ratio (OSR), unless otherwise noted.

**Figure 5. PSRR vs. Supply Ripple Frequency**

**Figure 6. CMRR vs. Common-Mode Ripple Frequency**

**Figure 7. SINAD vs. Analog Input Frequency**

**Figure 8. Typical Fast Fourier Transform (FFT)**

**Figure 9. Typical DNL Error**

**Figure 10. Typical INL Error**
Figure 11. Histogram of Codes at Code Center

Figure 12. SNR and SINAD vs. Temperature

Figure 13. THD and SFDR vs. Temperature

Figure 14. Offset vs. Temperature

Figure 15. Gain Error vs. Temperature

Figure 16. IDD1 vs. VDD1 at Various Temperatures and Clock Rates
Figure 17. IDD1 vs. VIN+ DC Input at Various Temperatures

Figure 18. IDD2 vs. VDD2 at Various Temperatures and Clock Rates

Figure 19. IDD2 vs. VIN+ DC Input at Various Temperatures

Figure 20. IIN+ vs. VIN+ DC Input at Various Clock Rates
TERMINOLOGY

Differential Nonlinearity (DNL)
DNL is the difference between the measured and the ideal 1 LSB change between any two adjacent codes in the ADC.

Integral Nonlinearity (INL)
INL is the maximum deviation from a straight line passing through the endpoints of the ADC transfer function. The endpoints of the transfer function are specified negative full scale, −250 mV (VIN+ − VIN−), Code 7168 for the 16-bit level, and specified positive full scale, +250 mV (VIN+ − VIN−), Code 58,368 for the 16-bit level.

Offset Error
Offset error is the deviation of the midscale code (32,768 for the 16-bit level) from the ideal VIN+ − VIN− (that is, 0 V).

Gain Error
The gain error includes both positive full-scale gain error and negative full-scale gain error. Positive full-scale gain error is the deviation of the specified positive full-scale code (58,368 for the 16-bit level) from the ideal VIN+ − VIN− (250 mV) after the offset error is adjusted out. Negative full-scale gain error is the deviation of the specified negative full-scale code (7168 for the 16-bit level) from the ideal VIN+ − VIN− (−250 mV) after the offset error is adjusted out.

Signal-to-Noise-and-Distortion Ratio (SINAD)
SINAD is the measured ratio of signal to noise and distortion at the output of the ADC. The signal is the rms value of the sine wave, and noise is the rms sum of all nonfundamental signals up to half the sampling frequency (fS/2), including harmonics, but excluding dc.

Signal-to-Noise Ratio (SNR)
SNR is the measured ratio of signal to noise at the output of the ADC. The signal is the rms amplitude of the fundamental. Noise is the sum of all nonfundamental signals up to half the sampling frequency (fS/2), excluding dc.

The ratio is dependent on the number of quantization levels in the digitization process: the greater the number of levels, the smaller the quantization noise. The theoretical signal-to-noise ratio for an ideal N-bit converter with a sine wave input is given by

\[
\text{Signal-to-Noise Ratio} = (6.02N + 1.76) \text{ dB}
\]

Therefore, for a 12-bit converter, the SNR is 74 dB.

Isolation Transient Immunity
The isolation transient immunity specifies the rate of rise and fall of a transient pulse applied across the isolation boundary, beyond which clock or data is corrupted. The AD7403 was tested using a transient pulse frequency of 100 kHz.

Total Harmonic Distortion (THD)
THD is the ratio of the rms sum of harmonics to the fundamental. For the AD7403, it is defined as

\[
\text{THD (dB)} = 20 \log \frac{\sqrt{V_1^2 + V_2^2 + V_3^2 + V_4^2}}{V_i}
\]

where:

\( V_i \) is the rms amplitude of the fundamental.
\( V_1, V_2, V_3, V_4, V_5, \) and \( V_6 \) are the rms amplitudes of the second through the sixth harmonics.

Peak Harmonic or Spurious Noise (SFDR)
Peak harmonic or spurious noise is defined as the ratio of the rms value of the next largest component in the ADC output spectrum (up to fS/2, excluding dc) to the rms value of the fundamental. Normally, the value of this specification is determined by the largest harmonic in the spectrum, but for ADCs where the harmonics are buried in the noise floor, it is a noise peak.

Effective Number of Bits (ENOB)
ENOB is defined by

\[
\text{ENOB} = (\text{SINAD} - 1.76)/6.02 \text{ bits}
\]

Noise Free Code Resolution
Noise free code resolution represents the resolution in bits for which there is no code flicker. The noise free code resolution for an N-bit converter is defined as

\[
\text{Noise Free Code Resolution (Bits)} = \log_2(2^N/\text{Peak-to-Peak Noise})
\]

The peak-to-peak noise in LSBs is measured with VIN+ = VIN− = 0 V.

Common-Mode Rejection Ratio (CMRR)
CMRR is defined as the ratio of the power in the ADC output at ±250 mV frequency, f, to the power of a +250 mV peak-to-peak sine wave applied to the common-mode voltage of VIN+ and VIN− of frequency, fS, as

\[
\text{CMRR (dB)} = 10 \log(P_f/P_{fS})
\]

where:

\( P_f \) is the power at frequency, f, in the ADC output.
\( P_{fS} \) is the power at frequency, fS, in the ADC output.

Power Supply Rejection Ratio (PSRR)
Variations in power supply affect the full-scale transition but not the linearity of the converter. PSRR is the maximum change in the specified full-scale (±250 mV) transition point due to a change in power supply voltage from the nominal value.
THEORY OF OPERATION

CIRCUIT INFORMATION

The AD7403 isolated Σ-Δ modulator converts an analog input signal into a high speed (20 MHz maximum), single-bit data stream; the time average single-bit data from the modulator is directly proportional to the input signal. Figure 21 shows a typical application circuit where the AD7403 is used to provide isolation between the analog input, a current sensing resistor or shunt, and the digital output, which is then processed by a digital filter to provide an N-bit word.

ANALOG INPUT

The differential analog input of the AD7403 is implemented with a switched capacitor circuit. This circuit implements a second-order modulator stage that digitizes the input signal into a single-bit output stream. The sample clock (MCLKIN) provides the clock signal for the conversion process as well as the output data framing clock. This clock source is external on the AD7403. The analog input signal is continuously sampled by the modulator and compared to an internal voltage reference. A digital stream that accurately represents the analog input over time appears at the output of the converter (see Figure 22).

A differential signal of 0 V ideally results in a stream of alternating 1s and 0s at the MDAT output pin. This output is high 50% of the time and low 50% of the time. A differential input of 250 mV produces a stream of 1s and 0s that are high 89.06% of the time. A differential input of −250 mV produces a stream of 1s and 0s that are high 10.94% of the time.

A differential input of 320 mV ideally results in a stream of all 1s. A differential input of −320 mV ideally results in a stream of all 0s. The absolute full-scale range is ±320 mV and the specified full-scale performance range is ±250 mV, as shown in Table 10.

Table 10. Analog Input Range

<table>
<thead>
<tr>
<th>Analog Input</th>
<th>Voltage Input (mV)</th>
</tr>
</thead>
<tbody>
<tr>
<td>Positive Full-Scale Value</td>
<td>+320</td>
</tr>
<tr>
<td>Positive Specified Performance Input</td>
<td>+250</td>
</tr>
<tr>
<td>Zero</td>
<td>0</td>
</tr>
<tr>
<td>Negative Specified Performance Input</td>
<td>−250</td>
</tr>
<tr>
<td>Negative Full-Scale Value</td>
<td>−320</td>
</tr>
</tbody>
</table>

Figure 21. Typical Application Circuit

Figure 22. Analog Input vs. Modulator Output
To reconstruct the original information, this output must be digitally filtered and decimated. A sinc3 filter is recommended because it is one order higher than that of the AD7403 modulator, which is a second-order modulator. If a 256 decimation rate is used, the resulting 16-bit word rate is 78.1 kSPS, assuming a 20 MHz external clock frequency. See the Digital Filter section for more detailed information on the sinc filter implementation. Figure 23 shows the transfer function of the AD7403 relative to the 16-bit output.

**Differential Inputs**

The analog input to the modulator is a switched capacitor design. The analog signal is converted into charge by highly linear sampling capacitors. A simplified equivalent circuit diagram of the analog input is shown in Figure 24. A signal source driving the analog input must provide the charge onto the sampling capacitors every half MCLKIN cycle and settle to the required accuracy within the next half cycle.

Because the AD7403 samples the differential voltage across its analog inputs, low noise performance is attained with an input circuit that provides low common-mode noise at each input.

**Digital Output**

The AD7403 MDAT output driver is a slew rate limited driver. This driver lowers electromagnetic emissions, thus minimizing electromagnetic interference, both conducted and radiated.
Applications Information

Current Sensing Applications

The AD7403 is ideally suited for current sensing applications where the voltage across a shunt resistor (RSHUNT) is monitored. The load current flowing through an external shunt resistor produces a voltage at the input terminals of the AD7403. The AD7403 provides isolation between the analog input from the current sensing resistor and the digital outputs. By selecting the appropriate shunt resistor value, a variety of current ranges can be monitored.

Choosing RSHUNT

The shunt resistor (RSHUNT) values used in conjunction with the AD7403 are determined by the specific application requirements in terms of voltage, current, and power. Small resistors minimize power dissipation, whereas low inductance resistors prevent any induced voltage spikes, and good tolerance devices reduce current variations. The final values chosen are a compromise between low power dissipation and accuracy. Higher value resistors use the full performance input range of the ADC, thus achieving maximum SNR performance. Low value resistors dissipate less power but do not use the full performance input range. The AD7403, however, delivers excellent performance, even with lower input signal levels, allowing low value shunt resistors to be used while maintaining system performance.

To choose a suitable shunt resistor, first determine the current through the shunt. The shunt current for a 3-phase induction motor can be expressed as

\[
I_{\text{RMS}} = \frac{P_W}{1.73 \times V \times EF \times PF}
\]

where:
- \(I_{\text{RMS}}\) is the motor phase current (A rms)
- \(P_W\) is the motor power (Watts)
- \(V\) is the motor supply voltage (V ac)
- \(EF\) is the motor efficiency (%)
- \(PF\) is the power efficiency (%)

To determine the shunt peak sense current, \(I_{\text{SENSE}}\), consider the motor phase current and any overload that may be possible in the system. When the peak sense current is known, divide the voltage range of the AD7403 (±250 mV) by the peak sense current to yield a maximum shunt value.

If the power dissipation in the shunt resistor is too large, the shunt resistor can be reduced and less of the ADC input range can be used. Figure 25 shows the SINAD performance characteristics and the ENOB of resolution for the AD7403 for different input signal amplitudes. Figure 26 shows the rms noise performance for dc input signal amplitudes. The AD7403 performance at lower input signal ranges allows smaller shunt values to be used while still maintaining a high level of performance and overall system efficiency.

Voltage Sensing Applications

The AD7403 can also be used for isolated voltage monitoring. For example, in motor control applications, it can be used to sense the bus voltage. In applications where the voltage being monitored exceeds the specified analog input range of the AD7403, a voltage divider network can be used to reduce the voltage being monitored to the required range.
INPUT FILTER

In a typical use case for directly measuring the voltage across a shunt resistor, the AD7403 can be connected directly across the shunt resistor with a simple RC low-pass filter on each input.

The recommended circuit configuration for driving the differential inputs to achieve best performance is shown in Figure 27. An RC low-pass filter is placed on both the analog input pins. Recommended values for the resistors and capacitors are 10 Ω and 220 pF, respectively. If possible, equalize the source impedance on each analog input to minimize offset.

![Figure 27. RC Low-Pass Filter Input Network](image)

The input filter configuration for the AD7403 is not limited to the low-pass structure shown in Figure 27. The differential RC filter configuration shown in Figure 28 also achieves excellent performance. Recommended values for the resistors and capacitor are 22 Ω and 47 pF, respectively.

![Figure 28. Differential RC Filter Network](image)

Figure 29 compares the typical performance for the input filter structures outlined in Figure 27 and Figure 28 for different resistor and capacitor values.

![Figure 29. SNR vs. Decimation Rate for Different Filter Structures for Different Resistor and Capacitor Values](image)

DIGITAL FILTER

The output of the AD7403 is a continuous digital bit stream. To reconstruct the original input signal information, this output bit stream needs to be digitally filtered and decimated. A sinc filter is recommended due to its simplicity. A sinc3 filter is recommended because it is one order higher than that of the AD7403 modulator, which is a second-order modulator. The type of filter selected, the decimation rate, and the modulator clock used determines the overall system resolution and throughput rate. The higher the decimation rate, the greater the system accuracy, as illustrated in Figure 30. However, there is a trade-off between accuracy and throughput rate and, therefore, higher decimation rates result in lower throughput solutions. Note that for a given bandwidth requirement, a higher MCLKIN frequency can allow higher decimation rates to be used, resulting in higher SNR performance.

![Figure 30. SNR vs. Decimation Rate for Different Sinc Filter Orders](image)

A sinc3 filter is recommended for use with the AD7403. This filter can be implemented on a field programmable gate array (FPGA) or a digital signal processor (DSP).

Equation 1 describes the transfer function of a sinc filter.

\[
H(z) = \left( \frac{1}{DR} \frac{1 - Z^{-DR}}{1 - Z^{-1}} \right)^N
\]  

where DR is the decimation rate and N is the sinc filter order.

The throughput rate of the sinc filter is determined by the modulator clock and the decimation rate selected.

\[
\text{Throughput} = \frac{MCLK}{DR}
\]

where MCLK is the modulator clock frequency

As the decimation rate increases, the data output size from the sinc filter increases. The output data size is expressed in Equation 3. The 16 most significant bits are used to return a 16-bit result.

\[
\text{Data size} = N \times \log_2(\text{DR})
\]
For a sinc^{3} filter, the −3 dB filter response point can be derived from the filter transfer function, Equation 1, and is 0.262 times the throughput rate. The filter characteristics for a third-order sinc filter are summarized in Table 11.

Table 11. Sinc3 Filter Characteristics for 20 MHz MCLKIN

<table>
<thead>
<tr>
<th>Decimation Ratio (DR)</th>
<th>Throughput Rate (kHz)</th>
<th>Output Data Size (Bits)</th>
<th>Filter Response (kHz)</th>
</tr>
</thead>
<tbody>
<tr>
<td>32</td>
<td>625</td>
<td>15</td>
<td>163.7</td>
</tr>
<tr>
<td>64</td>
<td>312.5</td>
<td>18</td>
<td>81.8</td>
</tr>
<tr>
<td>128</td>
<td>156.2</td>
<td>21</td>
<td>40.9</td>
</tr>
<tr>
<td>256</td>
<td>78.1</td>
<td>24</td>
<td>20.4</td>
</tr>
<tr>
<td>512</td>
<td>39.1</td>
<td>27</td>
<td>10.2</td>
</tr>
</tbody>
</table>

The following Verilog code provides an example of a sinc3 filter implementation on a Xilinx® Spartan®-6 FPGA. Note that the data is read on the positive clock edge. It is recommended to read in the data on the positive clock edge. The code is configurable to accommodate decimation rates from 32 to 4096.

```verilog
module dec256sinc24b(
    input mclk1,  /* used to clk filter */
    input reset,  /* used to reset filter */
    input mdata1, /* input data to be filtered */
    output reg [15:0] DATA, /* filtered output */
    output reg data_en,
    input [15:0] dec_rate
);
/* Data is read on positive clk edge */
reg [36:0] ip_data1;
reg [36:0] acc1;
reg [36:0] acc2;
reg [36:0] acc3;
reg [36:0] acc3_d2;
reg [36:0] diff1;
reg [36:0] diff2;
reg [36:0] diff3;
reg [36:0] diff1_d;
reg [36:0] diff2_d;
reg [15:0] word_count;
reg word_clk;
reg enable;
/*Perform the Sinc action*/
always @ (mdata1)
    if (mdata1==0)
        ip_data1 <= 37'd0; /* change 0 to a -1 for twos complement */
    else
        ip_data1 <= 37'd1;
/*Accumulator (Integrator)
Perform the accumulation (IIR) at the speed of the modulator.
always @ (negedge mclk1, posedge reset)
    begin
        if (reset)
            begin
                /* initialize acc registers on reset */
                acc1 <= 37'd0;
                acc2 <= 37'd0;
                acc3 <= 37'd0;
            end
        else
            begin
                /*perform accumulation process */
                acc1 <= acc1 + ip_data1;
                acc2 <= acc2 + acc1;
                acc3 <= acc3 + acc2;
            end
        end
/*decimation stage (MCLKOUT/WORD_CLK) */
always @ (posedge mclk1, posedge reset)
    begin
        if (reset)
            word_count <= 16'd0;
        else
            begin
                if ( word_count == dec_rate - 1 )
                    word_count <= 16'd0;
                else
                    word_count <= word_count + 16'b1;
            end
        end
always @ (posedge mclk1, posedge reset)
    begin
        if (reset)
            word_clk <= 1'b0;
        else
            begin
                if ( word_count == dec_rate - 1 )
                    word_clk <= 1'b1;
                else if ( word_count == dec_rate - 1 )
                    word_clk <= 1'b0;
            end
        end
/*Differentiator (including decimation stage)
Perform the differentiation stage (FIR) at a lower speed.
```
Z = one sample delay

\[ \text{WORD_CLK = output word rate} \]

```verilog
always @ (posedge word_clk, posedge reset)
begin
  if(reset)
  begin
    acc3_d2 <= 37'd0;
    diff1_d <= 37'd0;
    diff2_d <= 37'd0;
    diff1 <= 37'd0;
    diff2 <= 37'd0;
    diff3 <= 37'd0;
  end
  else
  begin
    diff1 <= acc3 - acc3_d2;
    diff2 <= diff1 - diff1_d;
    diff3 <= diff2 - diff2_d;
    acc3_d2 <= acc3;
    diff1_d <= diff1;
    diff2_d <= diff2;
  end
end

/* Synchronize Data Output*/
always@ (posedge mclk1, posedge reset)
begin
  if (reset)
  begin
    data_en <= 1'b0;
    enable <= 1'b1;
  end
  else
  begin
    if ( (word_count == dec_rate/2 - 1) && enable )
    begin
      data_en <= 1'b1;
      enable <= 1'b0;
    end
    else if ( (word_count == dec_rate - 1) && ~enable )
    begin
      data_en <= 1'b0;
      enable <= 1'b1;
    end
  end
end
```

Figure 32. Differentiator

Figure 33. Clocking Sinc3 Output into an Output Register
**INTERFACING TO ADSP-CM40xF**

The ADSP-CM40xF family of mixed-signal control processors contains on-chip sinc filter and clock generation modules for direct connection to the AD7403 MCLKIN and MDAT pins. The ADSP-CM40xF can process bit streams from four AD7403 devices using a pair of configurable sinc filters for each bit stream. The primary sinc filter of each pair produces the filtered and decimated output for the pair. The output can be decimated to any integer rate between 8 and 256 times lower than the input rate. The four secondary sinc filters are low latency filters with programmable positive and negative overrange detection comparators that can be used to detect system fault conditions.

Figure 34 shows the typical interface between the AD7403 and the ADSP-CM40xF. Additional information on the configuration of the sinc filter modules in the ADSP-CM40xF can be found in AN-1265.

**GROUNDING AND LAYOUT**

It is recommended to decouple the VDD1 supply with a 10 µF capacitor in parallel with a 1 nF capacitor to GND1. Decouple Pin 1 and Pin 7 individually. Decouple the VDD2 supply with a 100 nF value to GND2. In applications involving high common-mode transients, ensure that board coupling across the isolation barrier is minimized. Furthermore, design the board layout so that any coupling that occurs equally affects all pins on a given component side. Failure to ensure equal coupling can cause voltage differentials between pins to exceed the absolute maximum ratings of the device, thereby leading to latch-up or permanent damage. Place any decoupling used as close to the supply pins as possible.

Minimize series resistance in the analog inputs to avoid any distortion effects, especially at high temperatures. If possible, equalize the source impedance on each analog input to minimize offset. Check for mismatch and thermocouple effects on the analog input printed circuit board (PCB) tracks to reduce offset drift.

**INSULATION LIFETIME**

All insulation structures eventually break down when subjected to voltage stress over a sufficiently long period. The rate of insulation degradation is dependent on the characteristics of the voltage waveform applied across the insulation. In addition to the testing performed by the regulatory agencies, Analog Devices carries out an extensive set of evaluations to determine the lifetime of the insulation structure within the AD7403.

Analog Devices performs accelerated life testing using voltage levels higher than the rated continuous working voltage. Acceleration factors for several operating conditions are determined. These factors allow calculation of the time to failure at the actual working voltage. The values shown in Table 8 summarize the peak voltage for 20 years of service life for a bipolar, ac operating condition and the maximum VDE approved working voltages.

These tests subjected the AD7403 to continuous cross isolation voltages. To accelerate the occurrence of failures, the selected test voltages were values exceeding those of normal use. The time to failure values of these units were recorded and used to calculate the acceleration factors. These factors were then used to calculate the time to failure under the normal operating conditions. The values shown in Table 8 are the lesser of the following two values:

- The value that ensures at least a 20-year lifetime of continuous use.
- The maximum VDE approved working voltage.

Note that the lifetime of the AD7403 varies according to the waveform type imposed across the isolation barrier. The iCoupler insulation structure is stressed differently, depending on whether the waveform is bipolar ac, unipolar ac, or dc. Figure 35, Figure 36, and Figure 37 illustrate the different isolation voltage waveforms.
OUTLINE DIMENSIONS

Figure 38. 16-Lead Standard Small Outline Package, with Increased Creepage [SOIC_IC] Wide Body (RI-16-2)
Dimensions shown in millimeters

COMPLIANT TO JEDEC STANDARDS MS-013-AC

ORDERING GUIDE

<table>
<thead>
<tr>
<th>Model</th>
<th>Temperature Range</th>
<th>Package Description</th>
<th>Package Option</th>
</tr>
</thead>
<tbody>
<tr>
<td>AD7403BRIZ</td>
<td>−40°C to +125°C</td>
<td>16-Lead Standard Small Outline Package, with Increased Creepage [SOIC_IC]</td>
<td>RI-16-2</td>
</tr>
<tr>
<td>AD7403BRIZ-RL</td>
<td>−40°C to +125°C</td>
<td>16-Lead Standard Small Outline Package, with Increased Creepage [SOIC_IC]</td>
<td>RI-16-2</td>
</tr>
<tr>
<td>AD7403BRIZ-R7</td>
<td>−40°C to +125°C</td>
<td>16-Lead Standard Small Outline Package, with Increased Creepage [SOIC_IC]</td>
<td>RI-16-2</td>
</tr>
<tr>
<td>EVAL-AD7403FMCZ</td>
<td></td>
<td>16-Lead Standard Small Outline Package, with Increased Creepage [SOIC_IC] Evaluation Board System Demonstration Platform</td>
<td></td>
</tr>
<tr>
<td>EVAL-SDP-CH1Z</td>
<td></td>
<td>16-Lead Standard Small Outline Package, with Increased Creepage [SOIC_IC] Evaluation Board System Demonstration Platform</td>
<td></td>
</tr>
</tbody>
</table>

1 Z = RoHS Compliant Part.